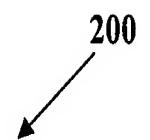
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1/3 100 Start 110 Identifying M design structures and N physical characteristics of the semiconductor circuit design. 120 For each of the M design structures, determining a fail rate of the design structure and determining whether the fail rate is high or low. For each of the N physical characteristics: 130 * Flagging the physical characteristic as being likely to contain at least a defect if every design structure of the M design structures in which the physical characteristic is present has a high fail rate, or * Determining that the physical characteristic should not be flagged as being likely to contain at least a defect if at least one design structure in which the physical characteristic is present has a low fail rate.

FIG. 1

Stop

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PC1	PC2	PC3	PC4	PC5	Fail	High Fail
					Rate	Rate
1	1	0	1	0	80%	1
0	1	0	1	0	10%	0
0	1	1	1	1	90%	1
0	0	0	1	1	15%	0
0	0	1	1	0	75%	1
0	0	0	1	0	30%	0
Yes	No	Yes	No	No		
	1 0 0 0 0	1 1 0 1 0 1 0 0 0 0 0 0 0 0 0 0	1 1 0 0 1 0 0 1 1 0 0 0 0 0 1 0 0 0 0 0 0 0 0 0	1 1 0 1 0 1 0 1 0 1 1 1 0 0 0 1 0 0 1 1 0 0 1 1 0 0 0 1	1 1 0 1 0 0 1 0 1 0 0 1 1 1 1 0 0 0 1 1 0 0 1 1 0 0 0 0 1 0 0 0 0 1 0	Rate 1 1 0 1 0 80% 0 1 0 1 0 10% 0 1 1 1 1 90% 0 0 0 1 1 15% 0 0 1 1 0 75% 0 0 0 1 0 30%

FIG. 2

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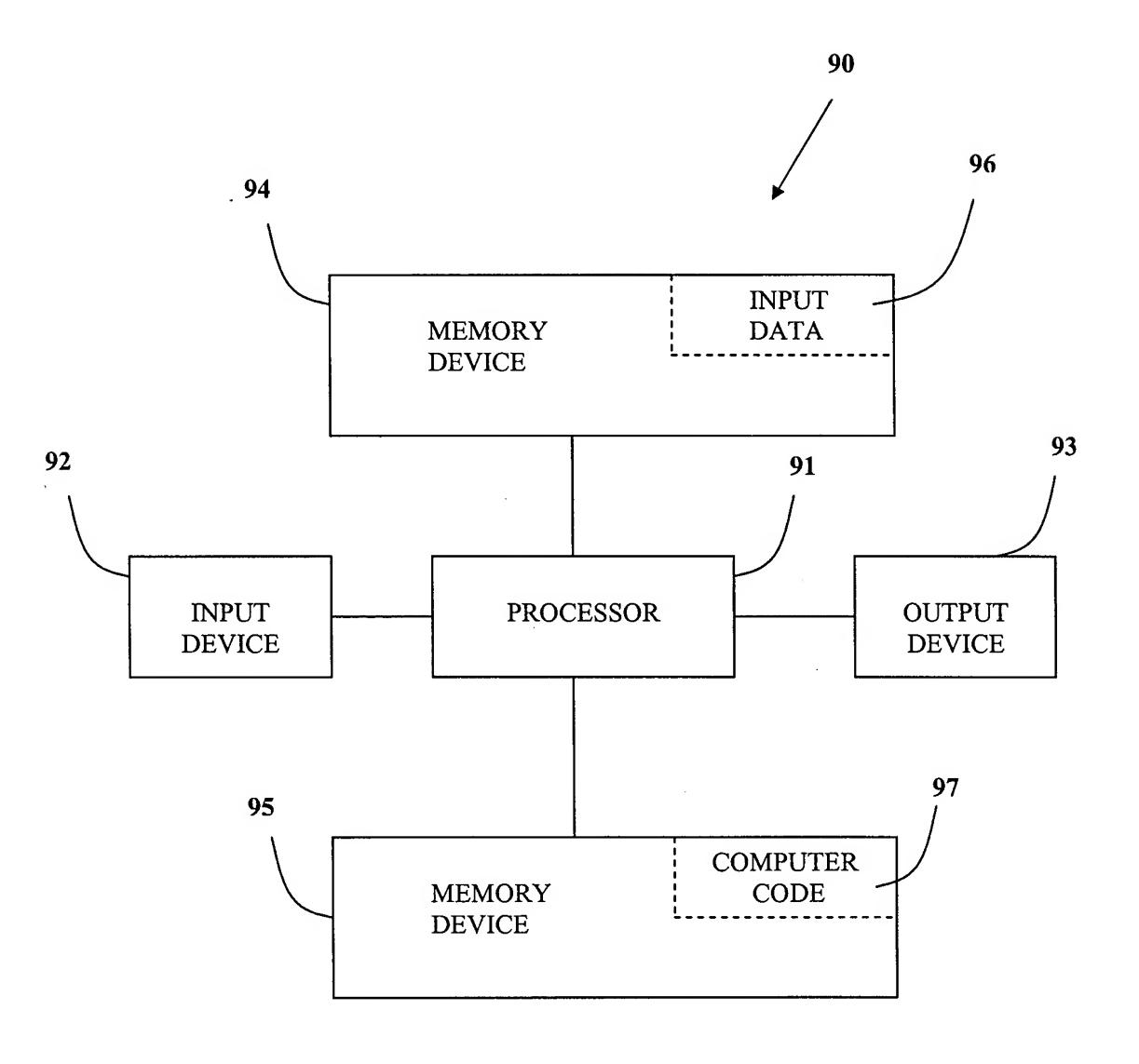


FIG. 3